

<b>Notice of References Cited</b>	Application/Control No. 10/805,995		Applicant(s)/Patent Under Reexamination SZREK ET AL.	
	Examiner Oluseye Iwarere		Art Unit 4127	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0049427	03-2004	Tami et al.	705/024
*	B	US-2005/0075938	04-2005	Mukai et al.	705/024
*	C	US-2005/0080681	04-2005	Ohnishi, Shinichi	705/024
*	D	US-2007/0233572	10-2007	Knowles et al.	705/022
*	E	US-5,734,719	03-1998	Tsevodos et al.	700/234
*	F	US-6,360,209	03-2002	Loeb et al.	705/34
*	G	US-6,434,535	08-2002	Kupka et al.	705/24
*	H	US-6,505,170	01-2003	Seifert et al.	705/21
*	I	US-6,553,346	04-2003	Walker et al.	705/1
*	J	US-6,748,365	06-2004	Quinlan et al.	705/14
*	K	US-6,961,710	11-2005	Yanagisawa et al.	705/24
*	L	US-6,965,869	11-2005	Tomita et al.	705/14
*	M	US-7,024,375	04-2006	Chau et al.	705/24

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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